

# Calculations of Optimal Source Geometry and Controlled Combinatorial Gradients in Fixed- and Rotating-Substrate PVD Systems

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# Calculations of Optimal Source Geometry and Controlled Combinatorial Gradients in Fixed- and Rotating-Substrate PVD Systems

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## ABSTRACT

Normalized forms of conventional flux-distribution formulas are applied to physical-vapor deposition from open-boat type sources onto static and rotating substrates. For the rotating-substrate case, the deposition geometry that yields optimal film-thickness uniformity for different source-substrate separations is derived empirically. In addition, flux-distribution formulas are used to develop a novel method for combinatorial physical-vapor deposition. With this method, a single deposition system may be used, without modification, to deposit either highly uniform or graded-composition thin-film materials.

## 1. Objectives

The goal of the Process Integration (PI) project at the National Renewable Energy Laboratory (NREL) is to integrate deposition, processing, and characterization techniques for research and development of thin-film, crystalline, and polycrystalline photovoltaic (PV) devices.<sup>1</sup> The purpose of this work is to explore the principles of deposition uniformity<sup>2-5</sup> to provide a starting point for the design of PI-compatible physical-vapor-deposition-(PVD-) based deposition and/or processing tools capable of uniform deposition on substrates up to 6" x 6" square. In addition, flux-distribution formulas for static and rotating substrates are employed to demonstrate a novel method for combinatorial thin-film synthesis that is applicable to the research of PV materials and devices.

## 2. Technical Approach

The deposition geometry used in this work is depicted in Fig. 1. For PVD sources that are characterized by a  $\cos\theta$  angular distribution, the substrate-radius-normalized formulas that express the flux distributions on static and rotating substrates, respectively, are

$$J_{static} = K \left( \frac{h_n^2}{R_s^2 (h_n^2 + \rho_n^2 + d_n^2 - 2\rho_n d_n \cos\phi)} \right), \text{ and } (1)$$

$$J_{rot} = K \left( \frac{h_n^2 (h_n^2 + \rho_n^2 + d_n^2)}{R_s^2 [(h_n^2 + \rho_n^2 + d_n^2)^2 - 4\rho_n^2 d_n^2]^{3/2}} \right), (2)$$

where  $K$  is a constant that depends on the evaporant material and temperature. The subscript 'n' denotes

geometrical parameters that are normalized with respect to substrate radius  $R_s$ , e.g.,  $h_n = h/R_s$ . Substrate radius is defined as the radius in the deposition plane over which film-thickness uniformity is required.

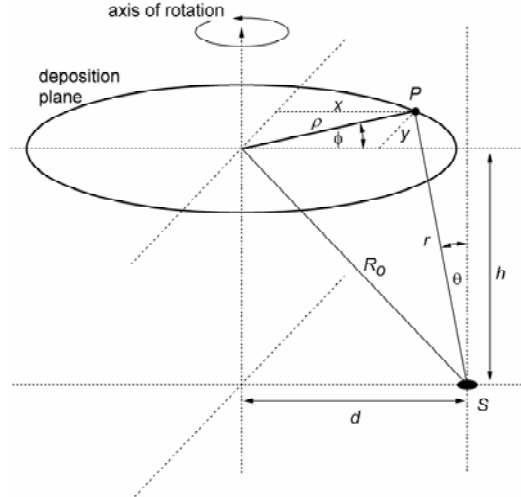


Fig. 1. Deposition geometry parameters.

Flux variation across the substrate is defined as

$$\text{flux variation} = \frac{J_{max} - J_{min}}{J_{max}}, (3)$$

where  $J_{max}$  and  $J_{min}$  are the maximum and minimum values of the flux for  $0 < \rho < R_s$ .

## 3. Results and Accomplishments

In this work, the deposition geometry that leads to optimal flux uniformity is determined empirically by systematically varying the source offset  $d_n$  for different values of the substrate height  $h_n$ , and then calculating the flux variation for each  $(h_n, d_n)$  combination according to Eq. (3). In addition, the basic flux-distribution formulas [Eqs. (1) and (2)] are extended to calculate the combinatorial gradients that are produced by specific deposition geometries when the substrate is static for part or all of the deposition.

### 3.1 Optimal Rotating-Substrate PVD Geometry

Analysis of Eqs. (1)–(3) demonstrates that optimal film-thickness uniformity is achieved when the source offset  $d_n$  is related to substrate height  $h_n$  according to

$$d_n \cong 0.180 + 0.681 \times h_n. (4)$$

Equation (4) is approximately valid for  $2 > h_n > 5$ , but might not hold in general outside of this range.

### 3.2 Novel Technique for Combinatorial PVD

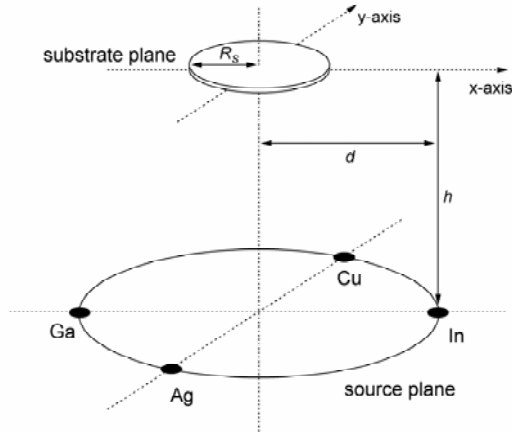


Fig. 2. Schematic of deposition-system geometry for uniform and combinatorial deposition of CAIGS. Complementary sources are placed in opposition on a circle in the source plane defined by Eq. (4).

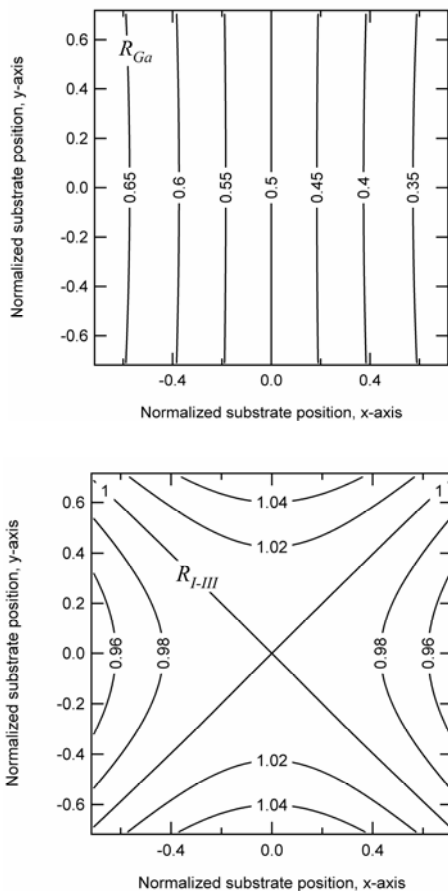


Fig. 3. Contour plots showing calculated Ga content [upper panel,  $R_{Ga} = Ga/(In+Ga)$ ] and Cu content [lower panel,  $R_{I-III} = Cu/(In+Ga)$ ] for combinatorial deposition of  $Cu(In,Ga)Se_2$ .

By performing part or all of a deposition onto a static substrate, it is possible to create combinatorial thin-film libraries with well-controlled compositional gradients. Figure 2 illustrates how sources might be arranged in a deposition system to study the  $(Cu,Ag)(In,Ga)Se_2$  materials system. Complementary metal sources are placed in opposition, and the Se source is not shown.

The deposition geometry in Fig. 2 is capable of producing highly uniform films (when the substrate is rotated during deposition) as well as graded-composition films (when the substrate is static during part or all of the deposition). An example of a combinatorial library sample that may be produced by this arrangement of sources is shown in Fig. 3. In this case, a CIGS thin film is deposited with no Ag. The substrate is rotated during the Cu deposition, and held static during the In+Ga deposition. The calculated Ga content [ $R_{Ga} = Ga/(In+Ga)$ ] varies from about 0.32 to 0.68, while the Cu content is nearly constant at all points on the substrate.

### 4. Conclusions

To facilitate design of PI-compatible tools, a condition for optimal-uniformity deposition during rotating-substrate PVD has been derived empirically. Also, a novel method for combinatorial thin-film PVD has been introduced that allows a single deposition tool, without modification, either to deposit highly uniform thin films or combinatorial thin-film libraries.

### ACKNOWLEDGEMENTS

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### REFERENCES

- <sup>1</sup>P. Sheldon, Prog. Photovolt., Res. Appl. (UK) **vol.8, no.1**, 77-91 (2000).
- <sup>2</sup>L. Holland and W. Steckelmacher, Vacuum **11**, 346-364 (1952).
- <sup>3</sup>K. H. Behrntd, 1963 transactions of the tenth National Vacuum Symposium of the American Vacuum Society, October 16-18, Boston, Massachusetts (1963).
- <sup>4</sup>B. S. Ramprasad, T. S. Radha, and M. Ramakrishna Rao, J. Vac. Sci. Technol. (USA) **vol.9, no.4**, 1227-1228 (1972).
- <sup>5</sup>H. A. Macleod, *Thin-film optical filters*, 3rd ed. (IOP Publishing, Bristol, England, 2001).

### MAJOR FY 2005 PUBLICATIONS

- G. Teeter, "Physical-vapor deposition flux-distribution calculations for static and rotating substrates: derivation of the deposition geometry for optimal film-thickness uniformity," submitted to J. Vac. Sci. Technol.-A.
- G. Teeter, "Conceptual design of a deposition system for uniform and combinatorial synthesis of multinary thin-film materials via open-boat physical-vapor deposition," submitted to J. Vac. Sci. Technol.-A.

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